

Planar Near-Field Range

Planar near-field systems provide another means of antenna measurement from which users can choose. In this configuration, the device under test is placed before a planar scanner which accurately measures the field by moving a probe through the two-dimensional plane. Unlike the spherical and cylindrical measurement systems, a planar near-field system only scans one side of the device in a given test. So planar near-field systems are most useful for measuring antennas with highly directional beam patterns.



The MI-350 Advanced Microwave Measurement Systems includes the basic instruments and software required for high-performance planar near-field measurements. It integrates the MI-3001 workstation and software environment using MI-3044 Planar Near-Field Analysis software option to command a fast and accurate combination of receiver, source and position control instruments. These instruments work with a full line of scanning and positioner solutions such as the the MI-6910 Family of Planar Scanners.

